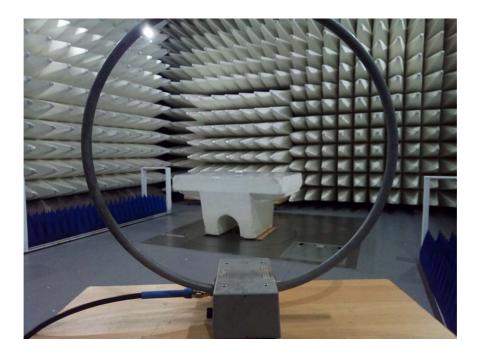


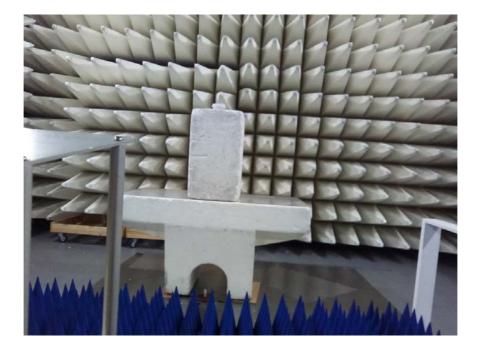
Photograph No.1 Setup for spurious emission field strength measurements in the anechoic chamber below 30 MHz



Photograph No.2 Setup for carrier and spurious emission field strength measurements in the anechoic chamber in 30 – 1000 MHz range

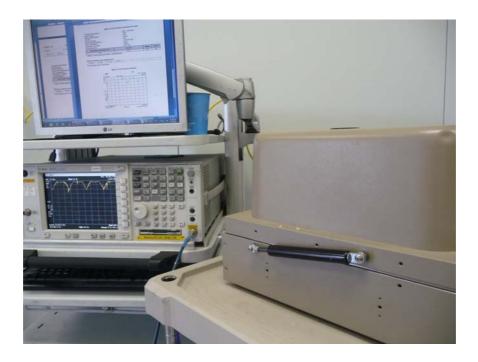


Photograph No.3 Setup for spurious emission field strength measurements in the anechoic chamber above 1000 MHz range



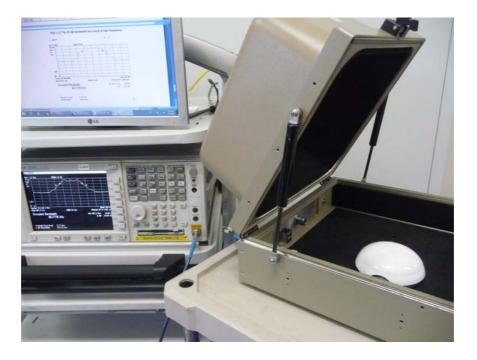


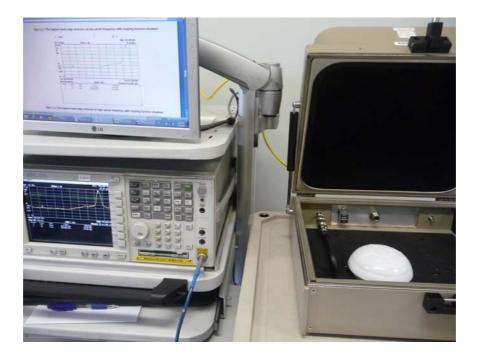
Photograph No.4 Setup for spurious emission field strength measurements, EUT close view



Photograph No.5 Setup for band edge emission and hopping parameters measurements

Photograph No.6 Setup for OBW measurements





Photograph No.7 Setup for band edge emission measurements